

Special Issue

Deep Learning and Digital Image Processing

Message from the Guest Editor

With the rapid development of artificial intelligence, deep learning technology, as an important subset of AI, enables models to autonomously infer results from structured datasets without the need for explicit human intervention. Deep learning has far surpassed traditional techniques and even human capabilities. Deep learning has achieved significant results in various image processing tasks, including image classification, object detection, image segmentation, and image enhancement. This Special Issue on “Deep Learning and Digital Image Processing” seeks high-quality research focusing on the basic principles, core algorithms, network structure designs, and specific applications in image processing of deep learning. Topics include, but are not limited to, the following:

1. Deep learning for image super-resolution; 2. Object detection, tracking, and recognition; 3. Deep learning for image segmentation; 4. Neural networks and deep learning; 5. Low-level visual understanding and image processing; 6. Feature extraction and feature selection; 7. Document analysis and recognition; 8. Activity recognition. etc.

Guest Editor

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Deadline for manuscript submissions

31 October 2025



Applied Sciences

an Open Access Journal
by MDPI

Impact Factor 2.5
CiteScore 5.5



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About the Journal

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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